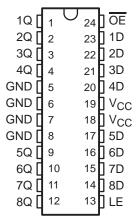
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- Eight Latches in a Single Package
- 3-State Bus Driving True Outputs
- Full Parallel Access for Loading
- Buffered Input and Output-Enable Pins
- Inputs Are TTL-Voltage Compatible
- Flow-Through Architecture Optimizes PCB Layout
- Center-Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-μm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline (DW) and Shrink Small-Outline (DB) Packages, and Standard Plastic 300-mil DIPs (NT)

DB, DW, OR NT PACKAGE (TOP VIEW)



description

This 8-bit latch features 3-state outputs designed specifically for driving highly-capacitive or relatively low-impedance loads. It is particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

The eight latches of the 74ACT11373 are transparent D-type latches. While the latch-enable (LE) input is high, the Q outputs follow the data (D) inputs. When the enable is taken low, the Q outputs are latched at the levels that were set up at the D inputs.

A buffered output-enable (\overline{OE}) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impendance third state and increased drive provide the capability to drive the bus lines in a bus-organized system without need for interface or pullup components.

OE does not affect the internal operations of the latches. Old data can be retained or new data can be entered while the outputs are off.

The 74ACT11373 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE (each latch)

	INPUTS		OUTPUT
OE	LE	D	Q
L	Н	Н	Н
L	Н	L	L
L	L	Χ	Q ₀
Н	Χ	Χ	Z



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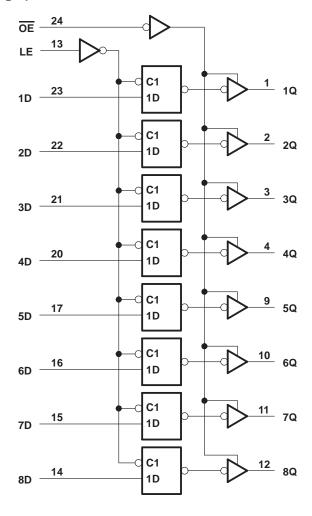
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logic symbol†

ŌĒ	24	EN				
LE	13	C1				
1D	23	1D	\triangleright	_	1	1Q
2D	22	110			2	2Q
3D	21			$\neg \neg$	3	3Q
4D	20	\vdash		\dashv	4	4Q
5D	17				9	5Q
	16	\vdash			10	6Q
6D	15	\vdash			11	
7D	14	\vdash			12	7Q
8D		<u> </u>				8Q

[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)





74ACT11373 OCTAL TRANSPARENT D-TYPE LATCH WITH 3-STATE OUTPUTS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	0.5 V to V _{CC} + 0.5 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±50 mA
Continuous current through V _{CC} or GND	±200 mA
Maximum power dissipation at $T_A = 55^{\circ}$ C (in still air) (see Note 2): DE	B package 0.65 W
DI	W package 1.7 W
N ⁻	T package 1.3 W
Storage temperature range, T _{stg}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

recommended operating conditions

		MIN	MAX	UNIT
Vcc	Supply voltage	4.5	5.5	V
VIH	High-level input voltage	2		V
VIL	Low-level input voltage		0.8	V
٧ı	Input voltage	0	VCC	V
٧o	Output voltage	0	VCC	V
IOH	High-level output current		-24	mA
loL	Low-level output current		24	mA
Δt/Δν	Input transition rise or fall rate	0	10	ns/V
TA	Operating free-air temperature	-40	85	°C



^{2.} The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils, except for the NT package, which has a trace length of zero.

74ACT11373 OCTAL TRANSPARENT D-TYPE LATCH WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		v	T _A = 25°C		MIN	MAX	UNIT	
PARAMETER	TEST CONDITION	15	vcc	MIN	TYP	MAX	IVIIIV	IVIAA	UNIT
	I 50 A		4.5 V	4.4			4.4		
	IOH = -50 μA			5.4			5.4		
VOН	I _{OH} = -24 mA	4	4.5 V	3.94			3.8		V
	10H = -24 IIIA		5.5 V	4.94			4.8		
	$I_{OH} = -75 \text{ mA}^{\dagger}$	Ę	5.5 V				3.85		
	I _{OL} = 50 μA		4.5 V			0.1		0.1	V
			5.5 V			0.1		0.1	
V _{OL}	I _{OL} = 24 mA		4.5 V			0.36		0.44	
			5.5 V			0.36		0.44	
	$I_{OL} = 75 \text{ mA}^{\dagger}$	Ę	5.5 V					1.65	
I _{OZ}	$V_O = V_{CC}$ or GND	Ę	5.5 V			±0.5		±5	μΑ
lį	$V_I = V_{CC}$ or GND	Ę	5.5 V			±0.1		±1	μΑ
ICC	$V_I = V_{CC}$ or GND, $I_O = 0$	Ę	5.5 V			8		80	μΑ
∆lCC [‡]	One input at 3.4 V, Other input	ts at GND or V _{CC}	5.5 V			0.9		1	mA
C _i	$V_I = V_{CC}$ or GND		5 V		4				pF
Co	$V_O = V_{CC}$ or GND		5 V		10				pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

		T _A = 25°C		MIN	MAX	UNIT
		MIN	MIN MAX		IVIAA	CINIT
t _W	Pulse duration, LE high	5		5		ns
t _{su}	Setup time, data before LE↓	3.5		3.5		ns
th	Hold time, data LE↓	3.5		3.5		ns

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	TO (OUTPUT)	T _A = 25°C			MIN	MAX	UNIT
PARAMETER	(INPUT)		MIN	TYP	MAX	IVIIIV	IVIAA	ONIT
tPLH	D	Q	1.5	7.5	10.3	1.5	11.8	
t _{PHL}	Б	ų ,	1.5	6.5	9.3	1.5	10	ns
t _{PLH}	LE	E Any O	1.5	8.5	11.3	1.5	13	ns
t _{PHL}		Any Q	1.5	8.5	10.9	1.5	12.2	115
^t PZH	ŌĒ	Any Q	1.5	7	10.7	1.5	12.5	ns
t _{PZL}	OE	Ally Q	1.5	7.5	10.9	1.5	12	115
^t PHZ	ŌĒ	Any O	1.5	10	12.1	1.5	12.2	ns
tPLZ	OE .	Any Q	1.5	7.5	9.5	1.5	10.1	115



[‡] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.

50% V_CC

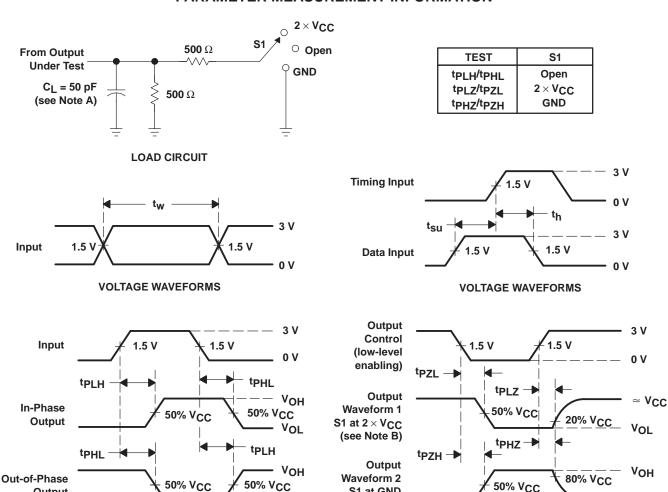
VOLTAGE WAVEFORMS

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operating characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER			TEST CO	TYP	UNIT	
C _{pd}	Power dissipation capacitance per latch	Outputs enabled	C ₁ = 50 pF. f = 1 MHz		65	25
		Outputs disabled	$C_L = 50 \text{ pF},$	f = 1 MHz	54	pF

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

VOLTAGE WAVEFORMS

Output

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \ \Omega$, $t_f = 3 \ ns$, $t_f = 3 \ ns$.

S1 at GND

(see Note B)

D. The outputs are measured one at a time with one input transition per measurement.

VOL

Figure 1. Load Circuit and Voltage Waveforms



≈ 0 V

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